

L Number	Hits	Search Text	DB	Time stamp
1	77763	414/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:27
2	416	414/\$.ccls. and ((die or chip or substrate or semiconductor) near3 (bond\$4 or stack\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:08
3	291	414/\$.ccls. and ((die or chip or semiconductor) near3 (bond\$4 or stack\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:30
4	11	(414/\$.ccls. and ((die or chip or semiconductor) near3 (bond\$4 or stack\$4))) and (introduc\$4 near3 wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:31
5	80782	((die or chip or semiconductor) near3 (bond\$4 or stack\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:30
6	278	((((die or chip or semiconductor) near3 (bond\$4 or stack\$4))) and (introduc\$4 near3 wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:31
7	0	(((((die or chip or semiconductor) near3 (bond\$4 or stack\$4))) and (introduc\$4 near3 wafer)) and ((introduc\$4 near3 wafer) with (stacker or bonder))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:31
8	0	((introduc\$4 near3 wafer) with (stacker or bonder))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:32
9	325	(wafer with (stacker or bonder))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:32
10	252	((wafer with (stacker or bonder))) and ((die or chip or substrate or semiconductor) near3 (bond\$4 or stack\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:08
11	672	438/455.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:08
12	484	438/455.ccls. and ((die or chip or substrate or semiconductor) near3 (bond\$4 or stack\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:52

13	117	438/455.ccls. and ((die or chip or substrate or semiconductor) near3 (stack\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:43
14	0	((((carrying or carried or convey\$4 or transfer\$4 or introduc\$4 or transport\$4) near4 wafer) with ((into or inside or in) near3 (bonder or stacker)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:48
15	38706	((carrying or carried or convey\$4 or transfer\$4 or introduc\$4 or transport\$4) near4 wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:47
16	42831	((carrying or carried or convey\$4 or transfer\$4 or introduc\$4 or transport\$4) near4 wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:47
17	16	((((carrying or carried or convey\$4 or transfer\$4 or introduc\$4 or transport\$4) near4 wafer) ) and ((into or inside or in) near3 (bonder or stacker)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:51
18	491	438/109.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:51
19	288	438/109.ccls. and ((die or chip or substrate or semiconductor) near3 stack\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:52
20	16	(438/109.ccls. and ((die or chip or substrate or semiconductor) near3 stack\$4)) and (bonder or stacker)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 13:52
21	8	(US-6560857-\$ or US-5979739-\$ or US-6566232-\$ or US-6177296-\$).did. or (US-20030145939-\$ or US-20020092622-\$ or US-20010013643-\$ or US-20030106209-\$).did.	USPAT; US-PGPUB	2003/11/25 13:56
22	14	(US-6514795-\$ or US-6337227-\$ or US-6620651-\$ or US-6506664-\$ or US-6376265-\$ or US-6165815-\$ or US-5952725-\$ or US-3591921-\$ or US-6617198-\$ or US-5804004-\$ or US-6428641-\$).did. or (US-20020004288-\$ or US-20030060034-\$ or US-20020185704-\$).did.	USPAT; US-PGPUB	2003/11/25 13:56
23	6	(US-5979739-\$ or US-6620651-\$ or US-5952725-\$ or US-5804004-\$ or US-3591921-\$).did. or (US-20010013643-\$).did.	USPAT; US-PGPUB	2003/11/25 14:24
-	143799	438/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:21
-	3103	438/\$.ccls. and (die near4 bond\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:27

-	346	(438/\$.ccls. and (die near4 bond\$4)) and (stack\$4 near4 (chip or die or device or semiconductor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:27
-	8	((438/\$.ccls. and (die near4 bond\$4)) and (stack\$4 near4 (chip or die or device or semiconductor))) and (die near3 bonder)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:27
-	104030	156/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:27
-	733	156/\$.ccls. and (die near4 bond\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:27
-	29	(156/\$.ccls. and (die near4 bond\$4)) and (stack\$4 near4 (chip or die or device or semiconductor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:31
-	4231	438/106,109,113,114,118,119.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 15:19
-	17583	(carrying or introducing) same wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:34
-	132	438/106,109,113,114,118,119.ccls. and ((carrying or introducing) same wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:35
-	14	(438/106,109,113,114,118,119.ccls. and ((carrying or introducing) same wafer)) and (((carrying or introducing) same wafer) same (die near4 bond\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:42
-	77	(((carrying or introducing) same wafer) same (die near4 bond\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:42
-	63	(((((carrying or introducing) same wafer) same (die near4 bond\$4))) not ((438/106,109,113,114,118,119.ccls. and ((carrying or introducing) same wafer)) and (((carrying or introducing) same wafer) same (die near4 bond\$4))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:42
-	15	(((((carrying or introducing) same wafer) same (die near4 bond\$4))) not ((438/106,109,113,114,118,119.ccls. and ((carrying or introducing) same wafer)) and (((carrying or introducing) same wafer) same (die near4 bond\$4)))) and stack\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 14:59
-	2	("6602773").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 15:18

-	4	("5863835"   "6001660"   "6011311"   "6066559").PN.	USPAT	2003/10/18 15:00
-	481	438/109.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 15:19
-	4	438/109.ccls. and ((die or chip or device or semiconductor) near4 (bonder))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/18 15:20
-	145296	438/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 10:22
-	241	438/\$.ccls. and ((die or chip or substrate or semiconductor) near3 bonder)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:01
-	23	(438/\$.ccls. and ((die or chip or substrate or semiconductor) near3 bonder)) and ((die or chip or substrate or semiconductor) near3 stack\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 10:37
-	422	438/458.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 10:35
-	59	438/458.ccls. and ((die or chip or substrate or semiconductor) near3 stack\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:01
-	2	(438/458.ccls. and ((die or chip or substrate or semiconductor) near3 stack\$4)) and ((die or chip or substrate or semiconductor) near3 bonder)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 11:44
-	57	(438/458.ccls. and ((die or chip or substrate or semiconductor) near3 stack\$4)) not ((438/458.ccls. and ((die or chip or substrate or semiconductor) near3 stack\$4)) and ((die or chip or substrate or semiconductor) near3 bonder))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 11:43
-	1218	438/118,119.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 11:44
-	36	438/118,119.ccls. and ((die or chip or substrate or semiconductor) near3 bonder)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 11:48
-	21	(438/118,119.ccls. and ((die or chip or substrate or semiconductor) near3 bonder)) and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 11:48

-	672	438/455.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 11:48
-	8	438/455.ccls. and ((die or chip or substrate or semiconductor) near3 bonder)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 11:51
-	2479	438/460-465.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 11:51
-	21	438/460-465.ccls. and ((die or chip or substrate or semiconductor) near3 bonder)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:28
-	2458	438/460-465.ccls. not (438/460-465.ccls. and ((die or chip or substrate or semiconductor) near3 bonder))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 11:55
-	90	(438/460-465.ccls. not (438/460-465.ccls. and ((die or chip or substrate or semiconductor) near3 bonder))) and ((die or chip or substrate or semiconductor) near3 stack\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:01
-	104462	156/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:01
-	75	156/\$.ccls. and ((die or chip or substrate or semiconductor) near3 bonder)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:01
-	3	(156/\$.ccls. and ((die or chip or substrate or semiconductor) near3 bonder)) and ((die or chip or substrate or semiconductor) near3 stack\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:05
-	79	((438/460-465.ccls. not (438/460-465.ccls. and ((die or chip or substrate or semiconductor) near3 bonder))) and ((die or chip or substrate or semiconductor) near3 stack\$4)) and wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/25 12:06